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SJ

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

SJ/T 2658.9-2015

Replacing SJ/T 2658.9-1986

**Measuring method for semiconductor infrared-emitting diode.
Part 9: Spatial distribution of radiant intensity and half-intensity
angle**

半导体红外发射二极管测量方法 第9部分：辐射强度空间分布和半强度角
(English Translation)

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What this standard covers

This standard specifies the measurement principle, measurement procedure and specified conditions of the spatial distribution and half intensity angle of the radiation intensity of semiconductor infrared emission diodes (hereinafter referred to as devices). This standard applies to semiconductor infrared emitting diodes.

Document data

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Standards quoted by this document

GB/T 2900.65-2004; GB/T 15651-1995; SJ/T 2658.1; SJ/T 2658.8; CIE 127-1997